IN THE SPECIFICATION:

Please replace the original paragraph 0001 on page 1 with the following amended paragraph.

[0001] The present application is related to U.S. Patent No. 7,206,012 B2 ~~patent application Ser. No. _____, Attorney Docket 2002-0711,~~ entitled "Memory Device On Optical Scanner And Apparatus And Method For Storing Characterizing Information On The Memory Device"; U.S. Patent No. 7,349,123 B2 ~~patent application Ser. No. _____, Attorney Docket 2003-0844,~~ entitled "Algorithms And Methods For Determining Laser Beam Process Direction Position Errors From Data Stored On A Printhead"; and U.S. Patent No. 7,375,738 B2 ~~patent application Ser. No. _____, Attorney Docket 2003-0839,~~ entitled "Electronic Systems And Methods For Reducing Laser Beam Process Direction Position Errors"; each of which is filed currently herewith and hereby incorporated by reference herein.

Please replace the original paragraph 0026 on page 6 with the following amended paragraph.

[0026] In order to derive each scan line linearity profile 34, the microprocessor 18 determines a measure of the laser beam scan line velocity changes from laser beam measurements 30, which, in the illustrated embodiment, are stored on a memory device 28 of the printhead 14. To clarify the context in which the laser beam measurements 30 are taken in the current embodiment, FIG. 2 illustrates a schematic representation of a laser system 24 from the perspective of the printhead 14 looking onto a print medium. The laser scanning system is similar to the one described in greater detail in U.S. Patent No. 7,349,123 B2 ~~patent application Ser. No. _____, Attorney Docket 2003-0844,~~ entitled "Algorithms And Methods For Determining Laser Beam Process Direction Position Errors From Data Stored On A Printhead"; which is already incorporated by reference herein.

Please replace the original paragraph 0037 on page 10 with the following amended paragraph.

[0037] The beam position measurements for each of the scan planes 108, 110, 112, 114 may be taken at some time during manufacturing of the apparatus and are stored in a memory device 28, e.g., a nonvolatile ram (NVRAM) device on the printhead 14, accessible to the microprocessor 18 in the controller 12. An exemplary approach to measuring points along a laser beam scan path is set out in U.S. Patent No. 7,206,012 B2 ~~patent application Ser. No. _____, Attorney Docket 2002-0711,~~ entitled "Memory Device On Optical Scanner And Apparatus And Method For Storing Characterizing Information On The Memory Device" to the same assignee, the contents of which are already incorporated by reference herein.

Please replace the original paragraph 0048 on page 13 with the following amended paragraph.

[0048] The angles discussed herein may be measured as is set out in U.S. Patent No. 7,206,012 B2 ~~patent application Ser. No. _____, Attorney Docket 2002-0711,~~ entitled "Memory Device On Optical Scanner And Apparatus And Method For Storing Characterizing Information On The Memory Device" to the same assignee, the contents of which are already incorporated by reference herein.

Please replace the original paragraph 0051 on page 13 with the following amended paragraph.

[0051] The process direction measurements (plotted on the Y-axis as shown in FIG. 2) are useful for computing a bow profile for performing process direction position errors as set out in detail in U.S. Patent No. 7,349,123 B2 ~~patent application Ser. No. _____, Attorney Docket 2003-0844,~~ entitled "Algorithms And Methods For Determining Laser Beam Process Direction Position Errors From Data Stored On A Printhead", which is already incorporated by reference herein.